



Features

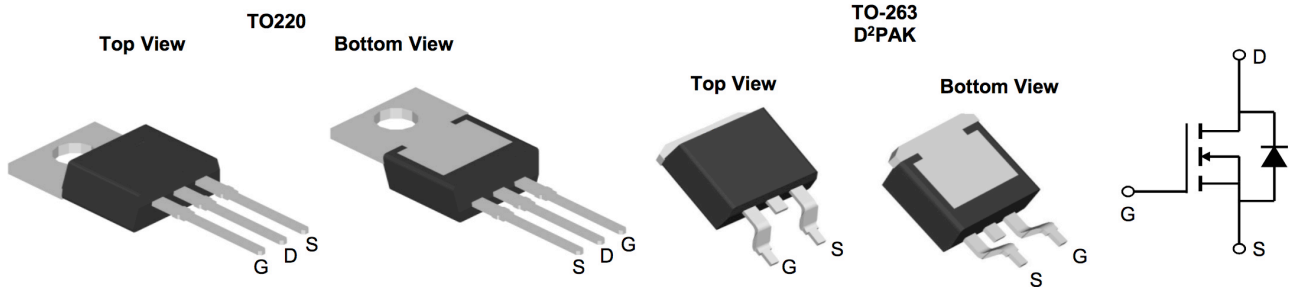
- 150V/150A
 $R_{DS(ON)} = 7.0m\Omega(Typ.)@V_{GS}=10V$
- Advanced HEFE[®] Technology
- Ultra Low On-Resistance
- Excellent $g_m \times R_{DS(on)}$ Product
- 100% avalanche tested
- 175°C Operating Temperature
- Lead Free and Green Devices Available (RoHS Compliant)

Applications

- Motor Drive
- Uninterruptible Power Supply
- DC/DC converter
- General Purpose Application



Pin Configurations



Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	150	V
V _{GS}	Gate-Source Voltage	±20	V
I _{D@T_C=25°C}	Continuous Drain Current, V _{GS} @ 10V	150	A
I _{D@T_C=100°C}	Continuous Drain Current, V _{GS} @ 10V	60	A
IDM	Pulsed Drain Current	520	A
EAS	Single Pulse Avalanche Energy	506	mJ
IAS	Avalanche Current	65	A
P _{D@T_C=25°C}	Total Power Dissipation ⁴	179	W
TSTG	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C
R _{θJA}	Thermal Resistance Junction-Ambient	25	°C/W
R _{θJC}	Thermal Resistance Junction-Case	0.75	°C/W

Product ID	Pack	Marking	Qty(PCS)
XPX150N15TU	TO-220-3L	XPX150N15TU XXX YYYY	1000
XPX150N15TU	TO-263-3L	XPX150N15TU XXX YYYY	800

150V N-Channel Enhancement Mode MOSFET
Electrical Characteristics (T_C=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	150	172	-	V
IGSS	Gate-body Leakage Current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
IDSS@T _J =25°C	Zero Gate Voltage Drain Current	V _{DS} = 150V, V _{GS} = 0V			1	μA
IDSS@T _J =100°C					100	
VGS(th)	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	3.2	4.5	V
RDS(on)	Drain-Source On-Resistance ⁴	V _{GS} = 10V, I _D = 20A	-	7.0	9.0	mΩ
gfs	Forward Transconductance ⁴	V _{DS} = 5V, I _D = 20A	-	60	-	S
Ciss	Input Capacitance	V _{DS} = 75V, V _{GS} = 0V, f = 1MHz	-	2181	-	pF
Coss	Output Capacitance		-	363	-	
Crss	Reverse Transfer Capacitance		-	7.9	-	
R _g	Gate Resistance		f = 1MHz	-	2.5	
Q _g	Total Gate Charge	V _{GS} = 10V, V _{DS} = 75V, I _D = 20A	-	30	-	nC
Q _{gs}	Gate-Source Charge		-	7.5	-	
Q _{gd}	Gate-Drain Charge		-	6.5	-	
td(on)	Turn-On Delay Time	V _{GS} = 10V, V _{DD} = 75V, R _G = 3Ω, I _D = 20A	-	12.5	-	ns
t _r	Rise Time		-	24	-	
td(off)	Turn-Off Delay Time		-	30	-	
t _f	Fall Time		-	26	-	
trr	Body Diode Reverse Recovery Time	I _F = 20A, dI/dt = 100A/μs	-	99	-	ns
Q _{rr}	Body Diode Reverse Recovery Charge		-	318	-	nC
VSD	Diode Forward Voltage ⁴	I _F = 20A, V _{GS} = 0V	-	-	1.2	V
IS	Continuous Source Current	T _C = 25°C	-	-	140	A

Notes:

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、 The EAS data shows Max. rating . The test condition is V_{DD}=50V, V_{GS}=10V, L=0.5mH, I_{AS}=65A
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

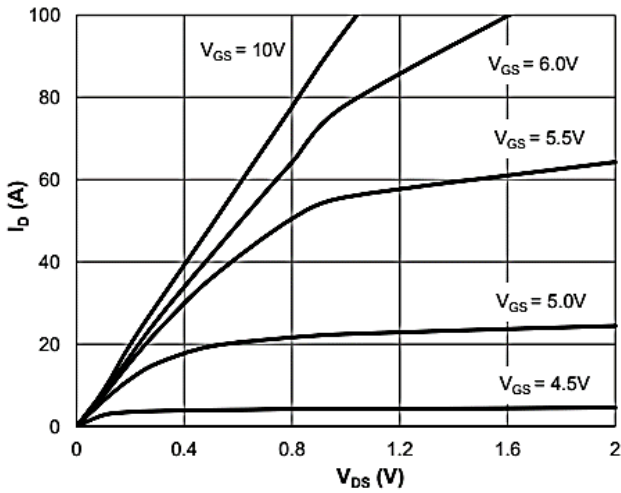


Figure 1: Saturation Characteristics

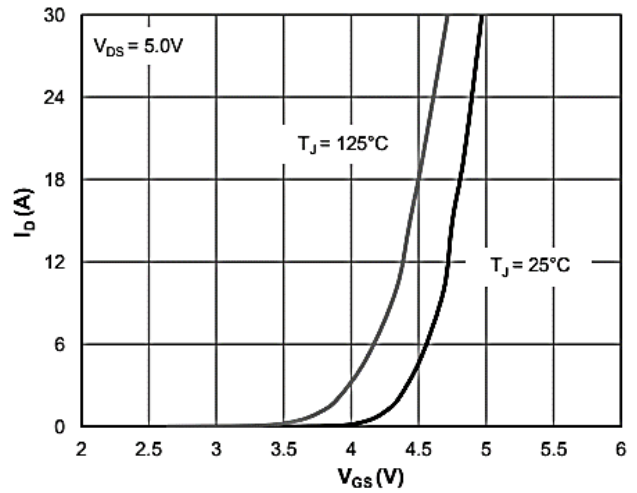


Figure 2: Transfer Characteristics

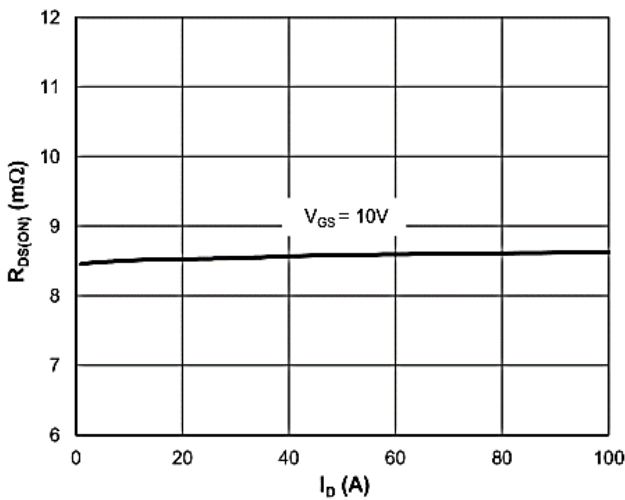


Figure 3: $R_{DS(ON)}$ vs. Drain Current

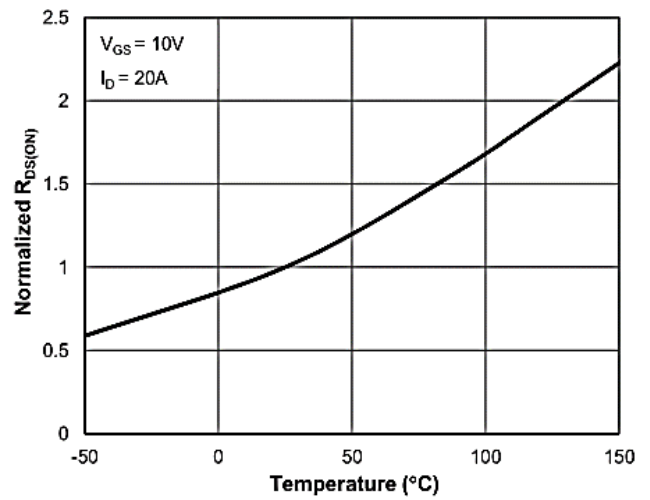


Figure 4: $R_{DS(ON)}$ vs. Junction Temperature

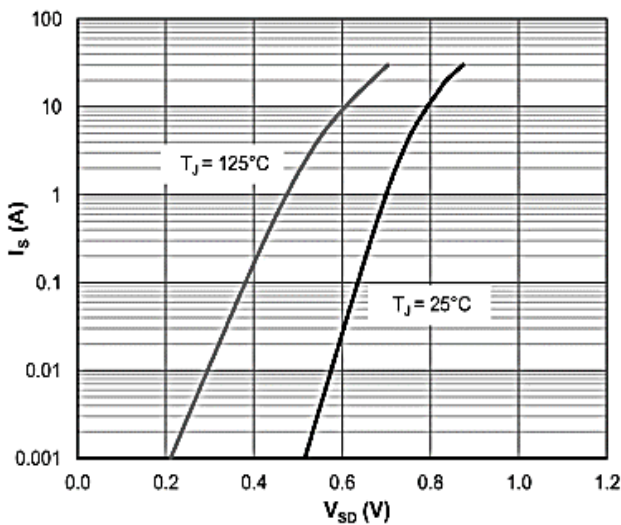


Figure 5: Body-Diode Characteristics

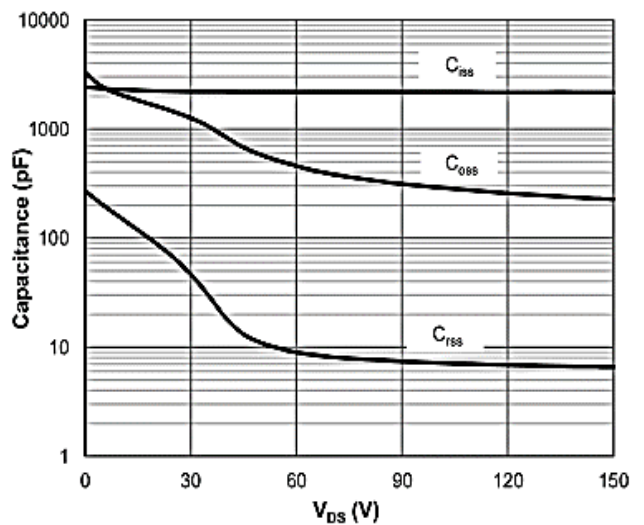


Figure 6: Capacitance Characteristics

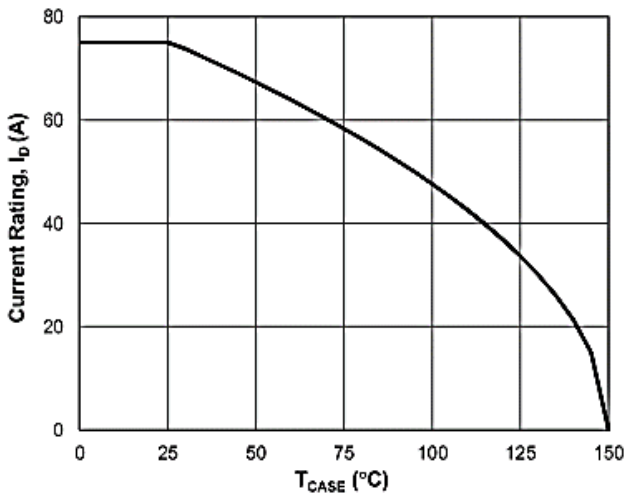


Figure 7: Current De-rating

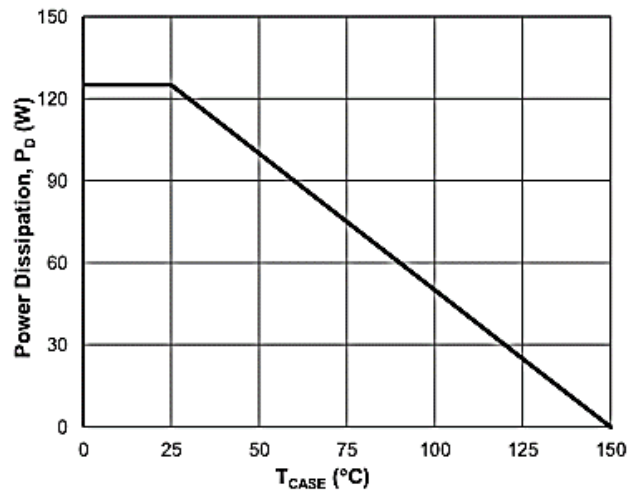


Figure 8: Power De-rating

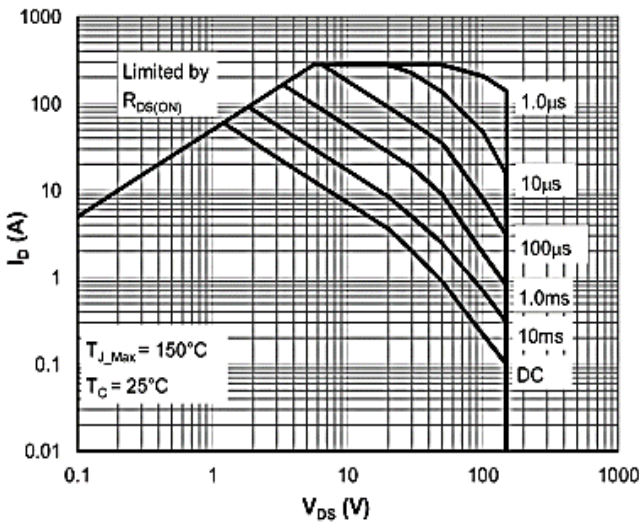


Figure 9: Maximum Safe Operating Area

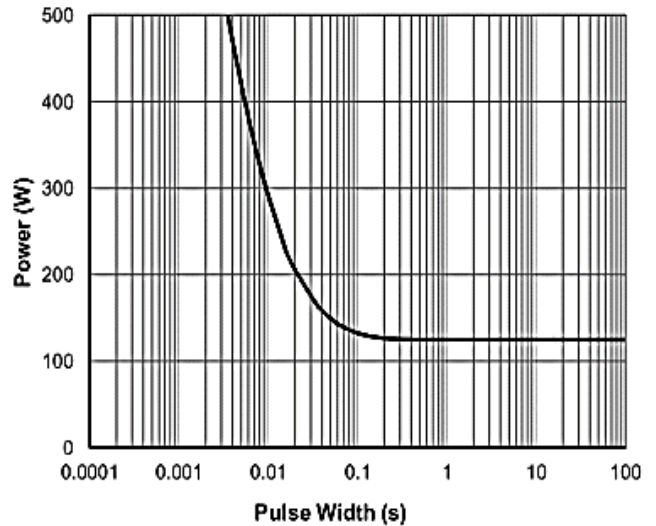


Figure 10: Single Pulse Power Rating, Junction-to-Case

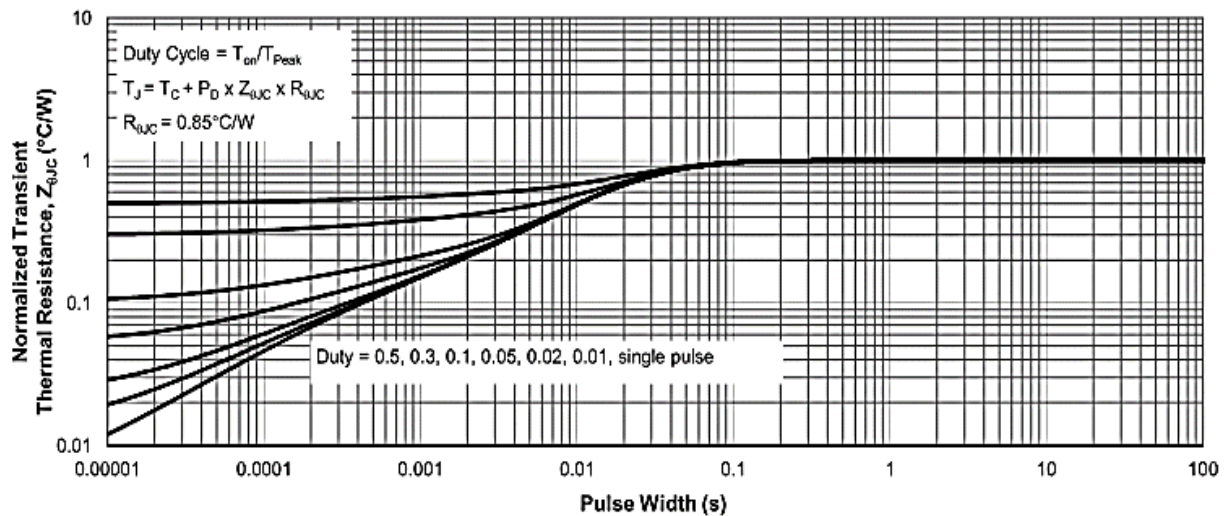
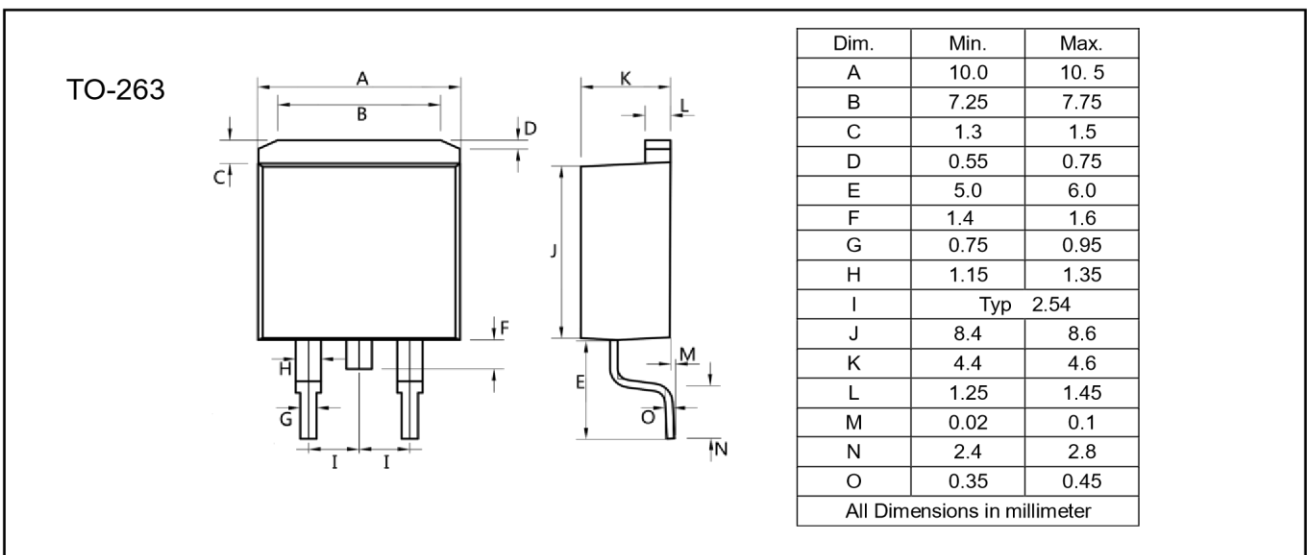
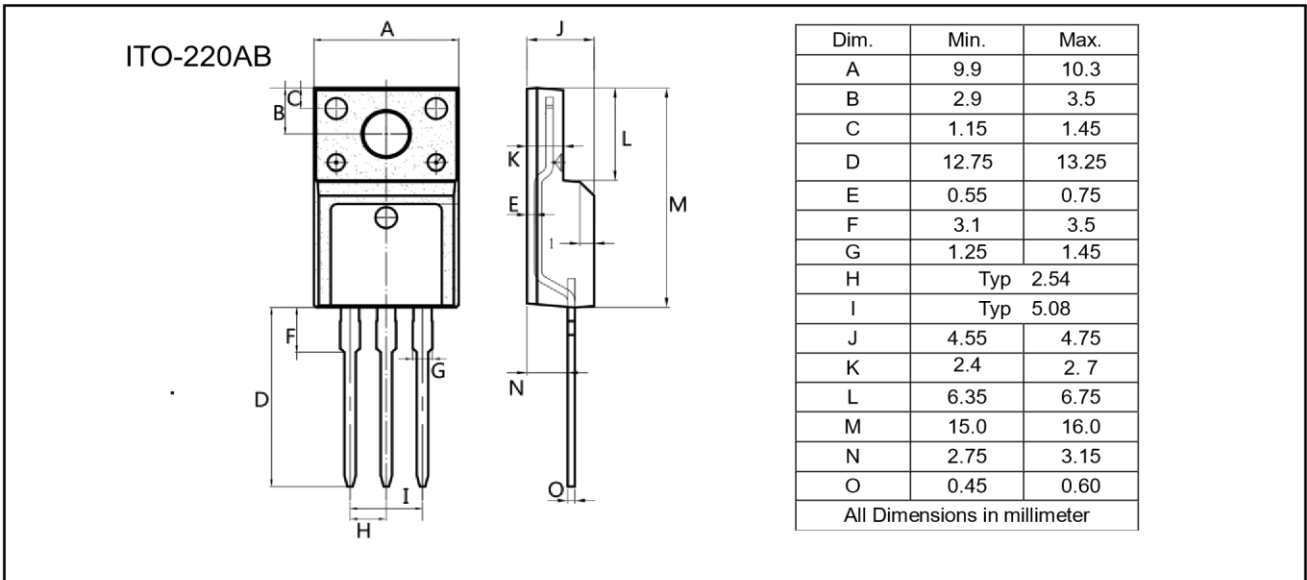
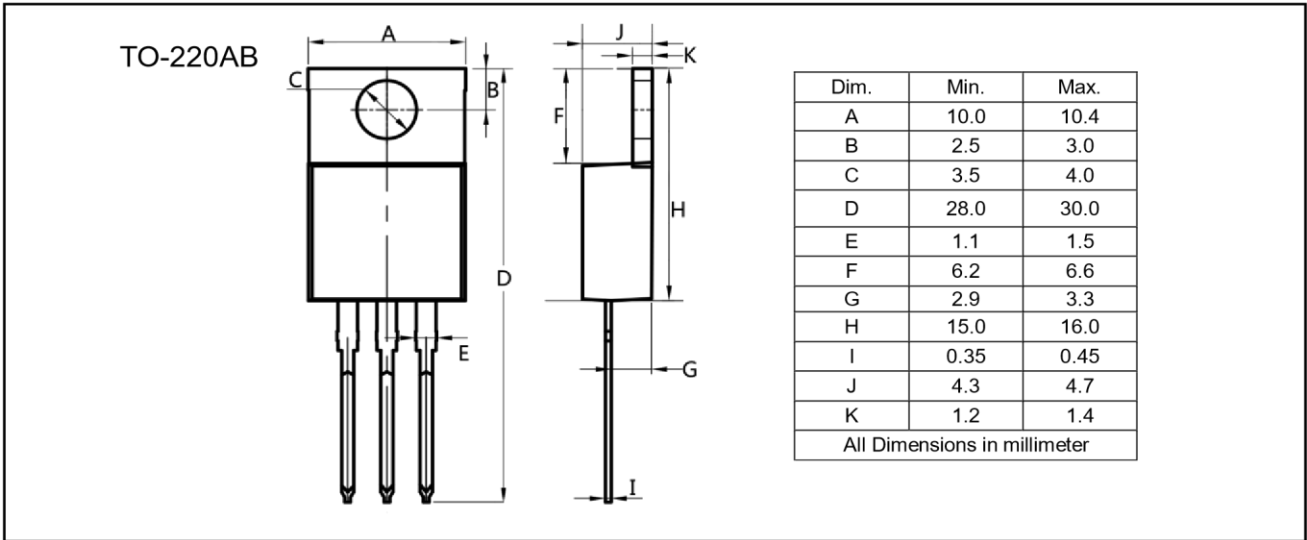


Figure 11: Normalized Maximum Transient Thermal Impedance



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec±1sec
Pb-Free device	260°C +0/-5°C	5sec±1sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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